TYPICAL SPECIFICATIONS

Representative Performance Data at 25°C

Table 1. PERFORMANCE DATA

Parameter	Min	Typ	Max	Units
Operating Bias Voltage	2.0		20	V
Capacitance (V_{bias} = 2 V)	2.32	2.70	2.97	pF
Capacitance (V_{bias} = 20 V)	0.73	0.77	0.81	pF
Tuning Range (2 V - 20 V)	3.00	3.50	4.05	
Tuning Range (20 V - 2 V)	2.80	3.30	4.05	
Leakage Current (Wafer Level)		270	540	nA
Leakage Current (WLCSP)			4.0	μA
Operating Frequency	700		2400	MHz
Quality Factor @ 900 MHz, 2 V		90		
Quality Factor @ 900 MHz, 20 V		90		
Quality Factor @ 1800 MHz, 2 V		70		
Quality Factor @ 1800 MHz, 20 V		70		
IP3 (V_{bias} = 2 V) [1,3]		68		dBm
IP3 (V_{bias} = 20 V) [1,3]		82		dBm
2nd Harmonic (V_{bias} = 2 V) [2,3]		−61		dBm
2nd Harmonic (V_{bias} = 20 V) [2,3]		−68		dBm
3rd Harmonic (V_{bias} = 2 V) [2,3]		−38		dBm
3rd Harmonic (V_{bias} = 20 V) [2,3]		−62		dBm
Transition Time (Cmin → Cmax) [4]		80		μs
Transition Time (Cmax → Cmin) [4]		70		μs

1. f_1 = 850 MHz, f_2 = 860 MHz, Pin 25 dBm/Tone
2. 850 MHz, Pin +34 dBm
3. IP3 and Harmonics are measured in the shunt configuration in a 50 Ω environment
4. RF1 and RF2 are both connected to DC ground

Representative performance data at 25°C for 2.7 pF WLCSP Package

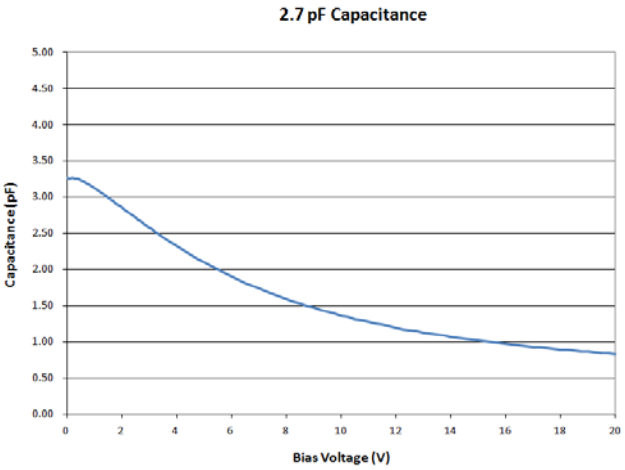


Figure 1. Capacitance

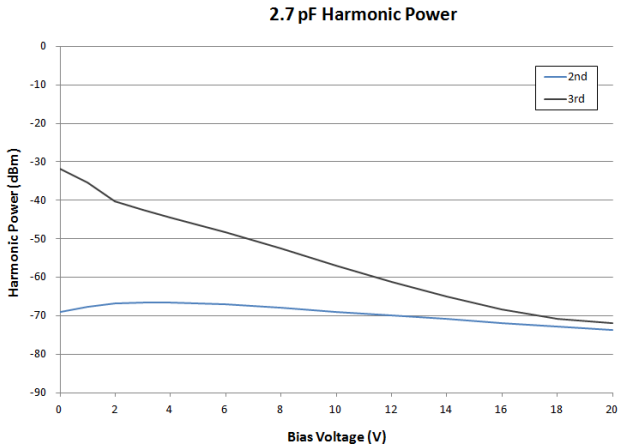


Figure 2. Harmonic Power

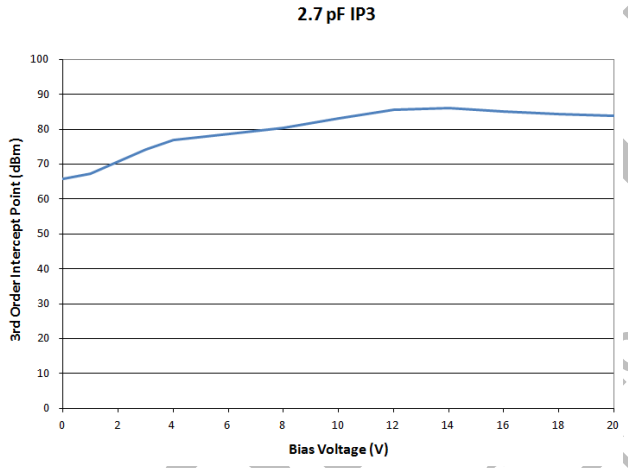


Figure 3. IP3

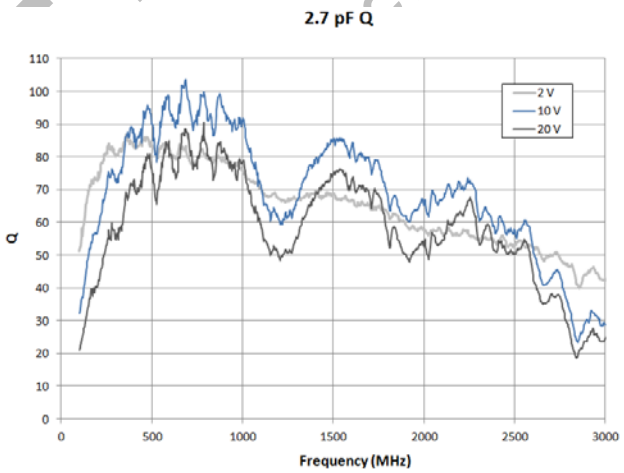


Figure 4. Q

Table 2. ABSOLUTE MAXIMUM RATINGS

Parameter	Rating	Units
Input Power	+40	dBm
Bias Voltage	+25 (Note 5)	V
Operating Temperature Range	−30 to +85	°C
Storage Temperature Range	−55 to +125	°C
ESD − Human Body Model	Class 1A JEDEC HBM Standard (Note 6)	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

5. WLCSP: Recommended Bias Voltage not to exceed 20 V
6. Class 1A defined as passing 250 V, but may fail after exposure to 500 V ESD pulse

ASSEMBLY CONSIDERATIONS AND REFLOW PROFILE

The following assembly considerations should be observed:

Cleanliness

These chips should be handled in a clean environment.

Electro-static Sensitivity

ON Semiconductor's PTICs are ESD Class 1A sensitive. The proper ESD handling procedures should be used.

Mounting

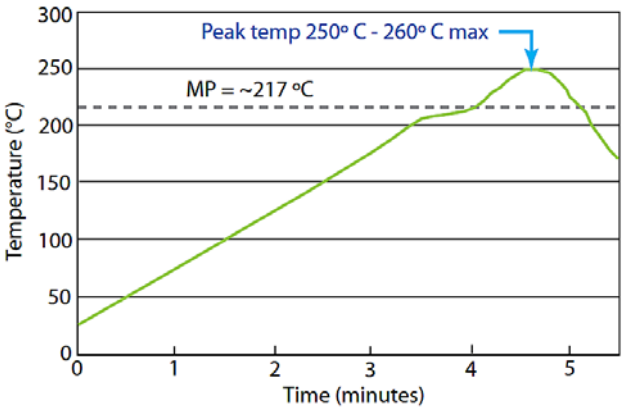
The WLCSP PTIC is fabricated for Flip Chip solder mounting. Connectivity to the RF and Bias terminations on the PTIC die is established through copper pillar posts (53 μm nominal height) topped with lead-free SAC351 solder caps (28 μm nominal height). The PTIC die is RoHS-compliant and compatible with lead-free soldering profile.

Post-reflow Cleaning

Use of ultrasonic cleaning is not recommended for pillared devices as it may lead to premature fatigue failure of the pillars.

Molding

The PTIC die is compatible for over-molding or under-fill.



This reflow profile is a guideline for Pb-free solder materials. Adjustments to this profile are necessary based on specific process requirements and board size, thickness and density.
Not to exceed 260° C for 5 seconds.

Figure 5. Reflow Profile

ORIENTATION OF THE PTIC FOR OPTIMUM LOSSES

When configuring the PTIC in your specific circuit design, at least one of the RF terminals must be connected to DC ground. If minimum transition times are required, DC ground on both RF terminals is recommended. To minimize losses, the PTIC should be oriented such that RF2 is at the lower RF impedance of the two RF nodes. A shunt PTIC, for example, should have RF2 connected to RF ground.

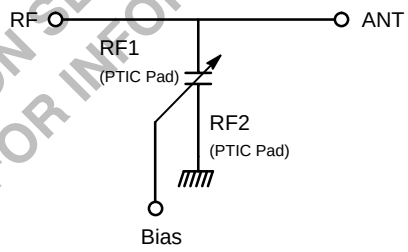


Figure 6. PTIC Orientation Functional Block Diagram

PART NUMBER DEFINITION

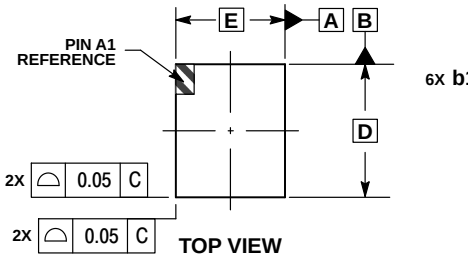
Table 3. PART NUMBERS

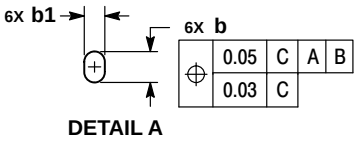
Part Number	Capacitance		Package
	2 V	20 V	
TCP-3027N-DT	2.70	0.77	8-Pillar WLCSP
TCP-3027N-QT	2.70	0.77	6-Pin QFN

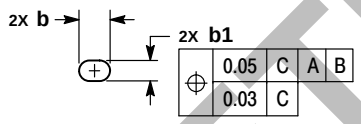
For information on device numbering and ordering codes, please download the *Device Nomenclature* technical note (TND310/D) from www.onsemi.com.

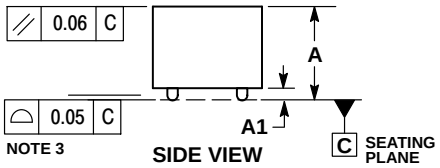
PACKAGE DIMENSIONS

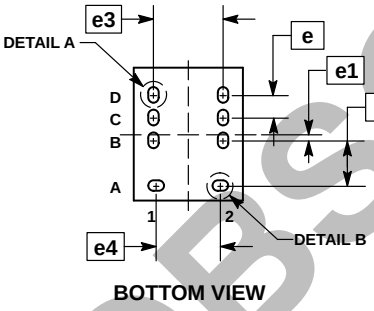
WLCSP8, 0.88x0.72
CASE 567KC
ISSUE A







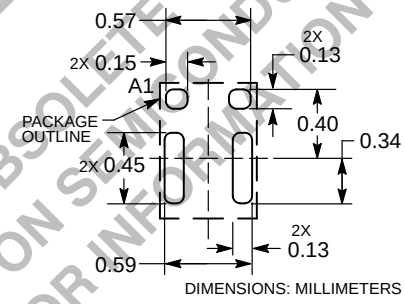




NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: MILLIMETERS.
3. COPLANARITY APPLIES TO SPHERICAL CROWNS OF SOLDER BALLS.

	MILLIMETERS	
DIM	MIN	MAX
A	0.590	0.639
A1	0.069	0.093
b	0.079	0.129
b1	0.044	0.094
D	0.879 BSC	
E	0.722 BSC	
e	0.150 BSC	
e1	0.031 BSC	
e2	0.300 BSC	
e3	0.460 BSC	
e4	0.425 BSC	

RECOMMENDED SOLDERING FOOTPRINT*

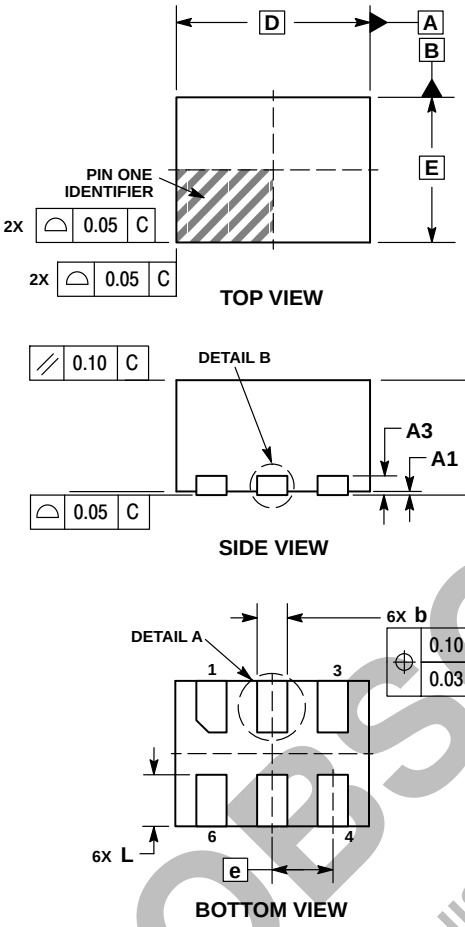


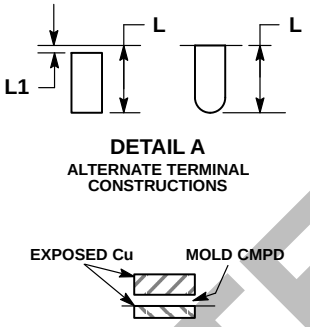
DIMENSIONS: MILLIMETERS

*For additional information on our Pb−Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

QFN6 1.6x1.2, 0.5P
CASE 485DX
ISSUE O

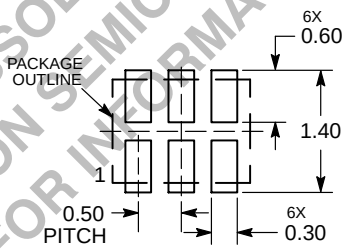




NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: MILLIMETERS.

	MILLIMETERS	
DIM	MIN	MAX
A	0.90	1.00
A1	0.00	0.05
A3	0.15 REF	
b	0.22	0.28
D	1.60 BSC	
E	1.20 BSC	
e	0.50 BSC	
L	0.39	0.46
L1	−−−	0.15

RECOMMENDED MOUNTING FOOTPRINT*



DIMENSIONS: MILLIMETERS

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